

Notice of References CitedApplication/Control No.
09/475,487Applicant(s)/Patent Under
Reexamination
ASSADI, AZARExaminer
Paul W MyersArt Unit
2612

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,501,065 B1	12-2002	Uppal et al.	250/214.1
	B	US-5,600,486 A	02-1997	Gal et al.	359/569
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	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Dictionary onlook.com definition: indium tin oxide
	V	Dictionary onlook.com definiton: silica□□
	W	Encyclopedia: Wikipedia definiton and use of silica
	X	Low-temperature sol-gel process developed, November 1997, SPIE Web, OP Reports

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.